



S/N 09/829,749
Docket: FIS920010045US1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Eddy, et al.

Serial No.: 09/829,749

Group Art Unit: 2858

Filed: April 10, 2001

Examiner: Dole, T.

For: INTERCONNECT PACKAGE CLUSTER PROBE SHORT REMOVAL
APPARATUS AND METHOD

Honorable Assistant Commissioner of Patents
Washington, D.C. 20231

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AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated September 23, 2002, please amend the
above-identified application as follows:

IN THE CLAIMS:

Please revise claim 1 to read as follows.

Sub B1

1. (Amended) An electronic circuit test and repair apparatus, comprising:

at least one wiring analyzer to locate shorts between conductors, said conductors
being on a surface of or embedded in a carrier substrate, said conductors being intended to
interconnect components to be mounted on said carrier substrate to form a circuit;
a current source to provide current sufficient to remove said shorts; and
at least two probes to contact said conductors in a manner controlled by said wiring
analyzer.

A1